

**Notice of References Cited**

Application/Control No.

09/760,137

Applicant(s)/Patent Under  
Reexamination  
LANE, ROBERT M.

Examiner

Etienne P LeRoux

Art Unit

2171

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0158885	08-2003	Sager, David J.	709/108
	B	US-4,621,318	11-1986	Maeda, Akira	711/158
	C	US-6,549,944	04-2003	Weinberg et al.	709/224
	D	US-5,440,750	08-1995	Kitai et al.	712/203
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

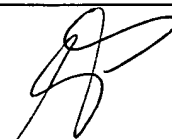
**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.



<b>Notice of References Cited</b>	Application/Control No. 09/760,137	Applicant(s)/Patent Under Reexamination LANE, ROBERT M.	
	Examiner Etienne P LeRoux	Art Unit 2171	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,530,079	03-2003	Choi et al.	717/158
	B	US-5,179,702	01-1993	Spix et al.	718/102
	C	US-5,940,827	08-1999	Hapner et al.	707/8
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

UT